


<b>Search Notes</b> 	<b>Application/Control No.</b> 10822064	<b>Applicant(s)/Patent Under Reexamination</b> MEYER ET AL.
	<b>Examiner</b> /Chang, Rick K	<b>Art Unit</b> 3726

SEARCHED			
Class	Subclass	Date	Examiner
29	832,834	11/25/07	rc
257	737,738,778,723		
438	108,115,118,666		

SEARCH NOTES			
Search Notes		Date	Examiner
east search		11/25/07	rc

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner